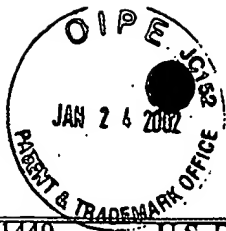




#2

U.S. Dept. of Commerce, Patent and Trademarks							
LIST OF ART CITED BY APPLICANT							
(Use several sheets if necessary)							
Attorney Docket No. A-6237		Serial No. 09/729,523		Filing Date DECEMBER 4, 2000			
Applicant: BACON ET AL.			Group 2131				
U.S. PATENT DOCUMENTS							
Examiner's Initial		Document No.	Date	Name	Class	Subclass	
AS	AA	5,425,101	6/13/95	Woo et al.	—	RECEIVED	
AS	AB	5,838,873	11/17/98	Blatter et al.	—	JUN 18 2001	
AS	AC	5,936,660	8/10/99	Gurantz	—	Technology Center 2100	
	AD						
	AE						
FOREIGN PATENT DOCUMENTS							
		Document No.	Date	Country	Class	Subclass	Translation
AS	AF	EP 0 893 921	1/27/99	Europe	—	—	
AS	AG	WO 99/57889	11/11/99	PCT International	—	—	
	AH						
	AI						
OTHER PRIOR ART (Including Author Title, Date, Pertinent Pages, Etc.)							
	AJ						
	AK						
	AL						
EXAMINER A. Sherkat				DATE CONSIDERED: 5/03/04			
EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance. Include copy of this form with next communication to Applicant.							



#3

Form PTO-1449 U.S. Dept. of Commerce, Patent and Trademarks LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)							
Attorney Docket No. A-6237		Serial No. 09/729,523		Filing Date DECEMBER 4, 2000			
Applicant: BACON ET AL.			Group 2131				
U.S. PATENT DOCUMENTS							
Exami ner's Initial		Document No.	Date	Name	Class	Subclass	
A.S	AA	5,903,314	5/11/99	Nijima et al.	348	564	
	AB						
	AC						
	AD						
	AE						
FOREIGN PATENT DOCUMENTS							
		Document No.	Date	Country	Class	Subclass	Translation
	AF						
	AG						
	AH						
	AI						
OTHER PRIOR ART (Including Author Title, Date, Pertinent Pages, Etc.)							
	AJ						
	AK						
	AL						
EXAMINER <i>A. S. Heston</i>				DATE CONSIDERED: 5/3/04			
EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance. Include copy of this form with next communication to Applicant.							

RECEIVED

JAN 29 2002

Technology Center 2100